

# **A Geometrical Phenomenon: Support Vector Machines and Linear Regression Coincide With Very High Dimensional Features**

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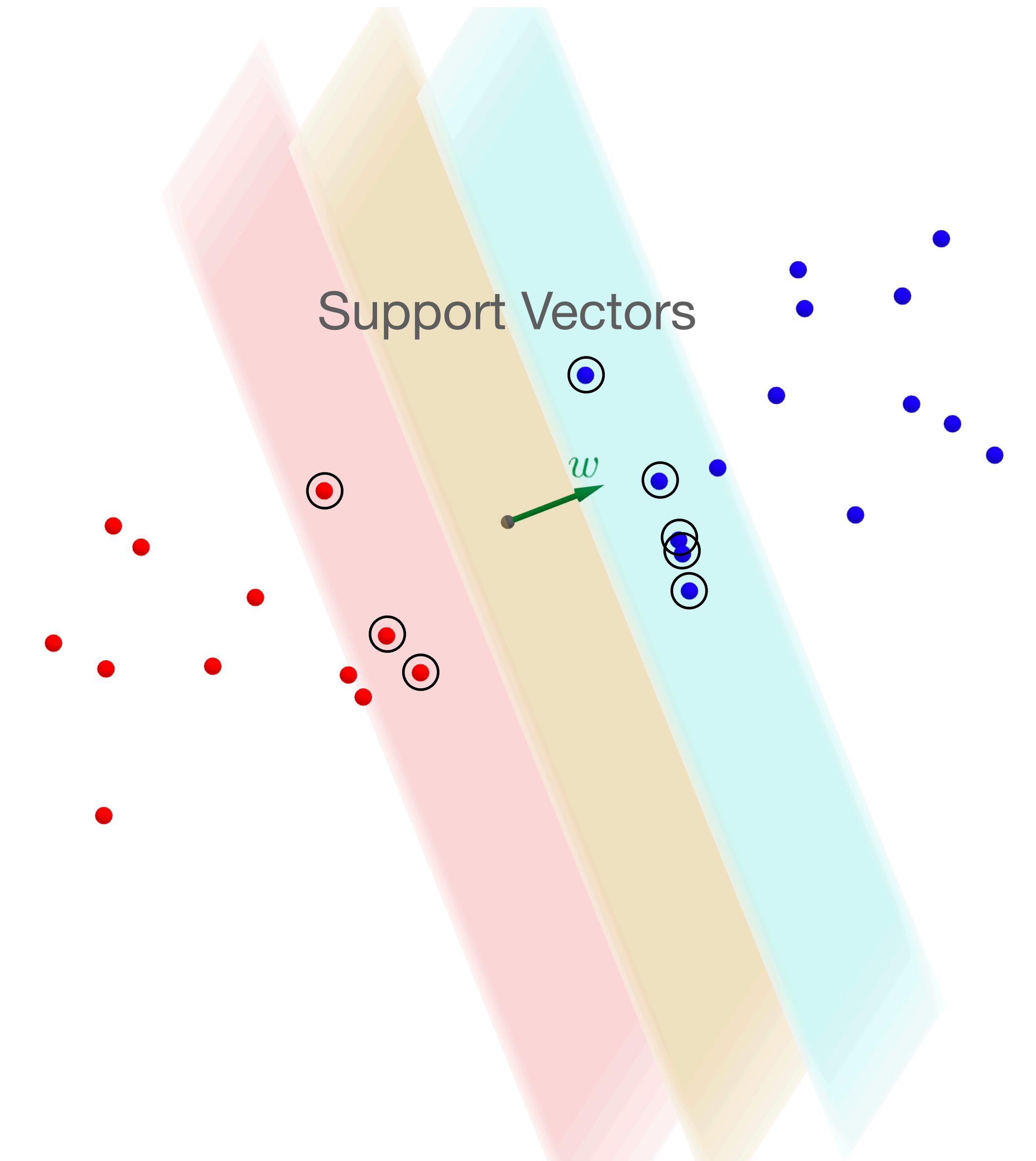
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**Based on joint work with Clayton Sanford and Daniel Hsu**



# Introduction

- High Dimensional **Regression** and **Classification**
  - **Regression:** Min Norm Linear Regression (**OLS**)
  - **Classification:** Max Margin Linear Classifier (**SVM**)



# **Surprise in High Dimensional Regression and Classification:**

**OLS = SVM**



**Support Vector Proliferation (SVP)**

# Outline

- Inductive bias of learning
  - Linear and logistic regression
- Classification vs. regression
  - **OLS = SVM** and its implications
  - Our results
  - Key lemma and geometrical intuition
  - Proof ideas
  - Empirical universality

# Inductive bias

- The inductive bias is simply the set of assumptions that learner makes about inherent properties of the data.
- Deep learning practice:
  - Choice of architecture, e.g. CNN, Resnet18, etc.
  - Choice of **loss function**, e.g. square loss, logistic loss, etc.
  - Choice of optimization procedure, e.g. GD, SGD, Mirror Descent, etc.
- All these choices constitutes as inductive bias!

# Inductive bias - regression

- **Question:** Given samples  $(x_1, y_1), \dots, (x_n, y_n) \in \mathbb{R}^d \times \mathbb{R}$  what is the inductive bias of certain optimization procedures for **linear regression**?
- Linear Regression:  $\mathcal{H} = \{x \mapsto w^\top x\}$ .
- The goal of ERM learner is to find an estimator/classifier  $h_w(x) = w^\top x$  such that it minimizes the empirical risk,  $\hat{R}(h_w) = \frac{1}{n} \sum_{i=1}^n (y_i - h_w(x_i))^2$ .
- When  $d > n$ , there could be infinitely-many minimizers in  $\arg \min_{h \in \mathcal{H}} \hat{R}(h)$ .

# Inductive bias - regression

**Theorem: [Werner Engl, et al. '96]**

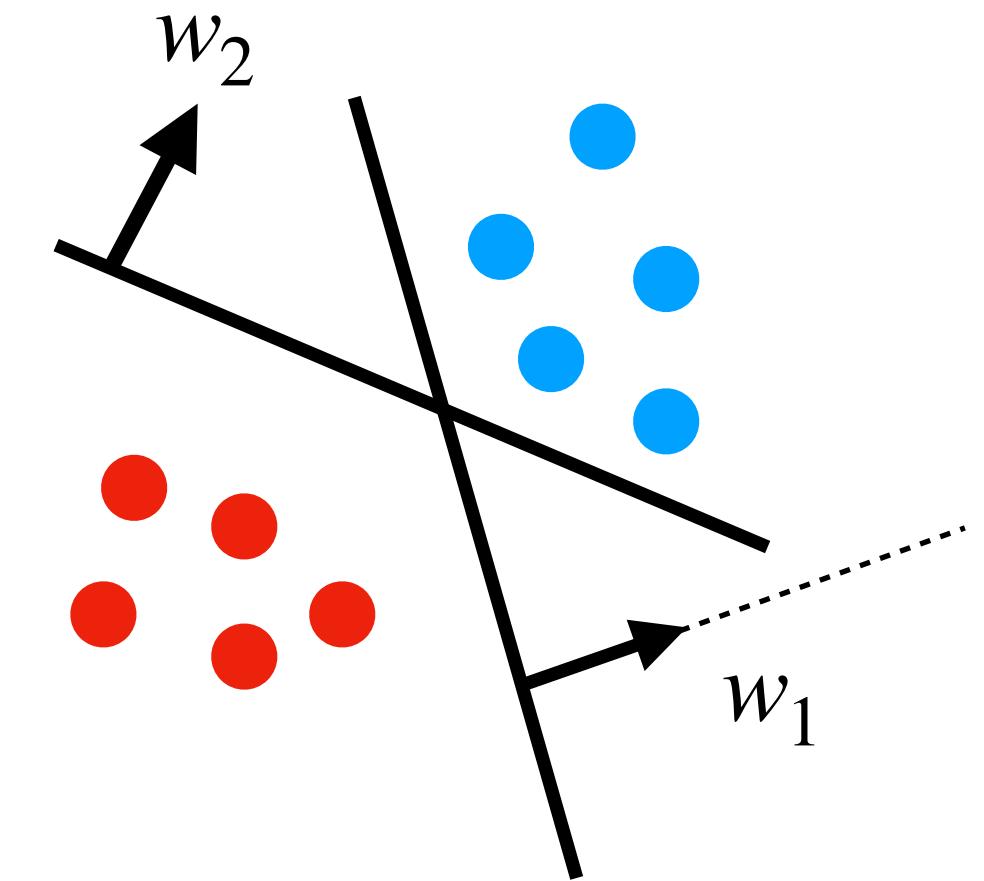
For a feasible set of linear equations, the evolution of GD with initialization at zero converges to the **minimum Euclidean norm linear interpolator (OLS)**,

$$\lim_{t \rightarrow \infty} w_t = \arg \min_{w \in \mathbb{R}^d} \|w\|_2 \quad \text{s.t.} \quad w^\top x_i = y_i.$$

- Minimum  $\ell_p$ -norm interpolators ( $\ell_p$ -OLS) can be obtained by Steepest Descent on the dual norm [Gunasekar, et al. '18].

# Inductive bias - classification

- **Question:** Given  $(x_1, y_1), \dots, (x_n, y_n) \in \mathbb{R}^d \times \{\pm 1\}^n$  samples, what is the inductive bias of certain optimization procedures for **logistic regression**?
- Logistic regression:  $\mathcal{H} = \{x \mapsto w^\top x \mid w \in \mathbb{R}^d\}$ .
- The goal is to minimize  $\hat{R}(h_w) = -\frac{1}{n} \sum_{i=1}^n \log(1 + e^{-y_i h_w(x_i)})$ .
- Linear separable: there exists a linear classifier with zero training classification error.
- When data is separable there may be infinitely-many empirical minimizers at infinity.



# Inductive bias - classification

**Theorem: [Soudry, et al. '18]**

For linearly separable data, the evolution of GD with any initialization converges to the **hard margin support vector machine (SVM)**,

$$\lim_{t \rightarrow \infty} \frac{w_t}{\|w_t\|_2} = \frac{w^*}{\|w^*\|_2}, \quad w^* = \arg \min_{w \in \mathbb{R}^d} \|w\|_2 \quad \text{s.t.} \quad y_i w^\top x_i \geq 1.$$

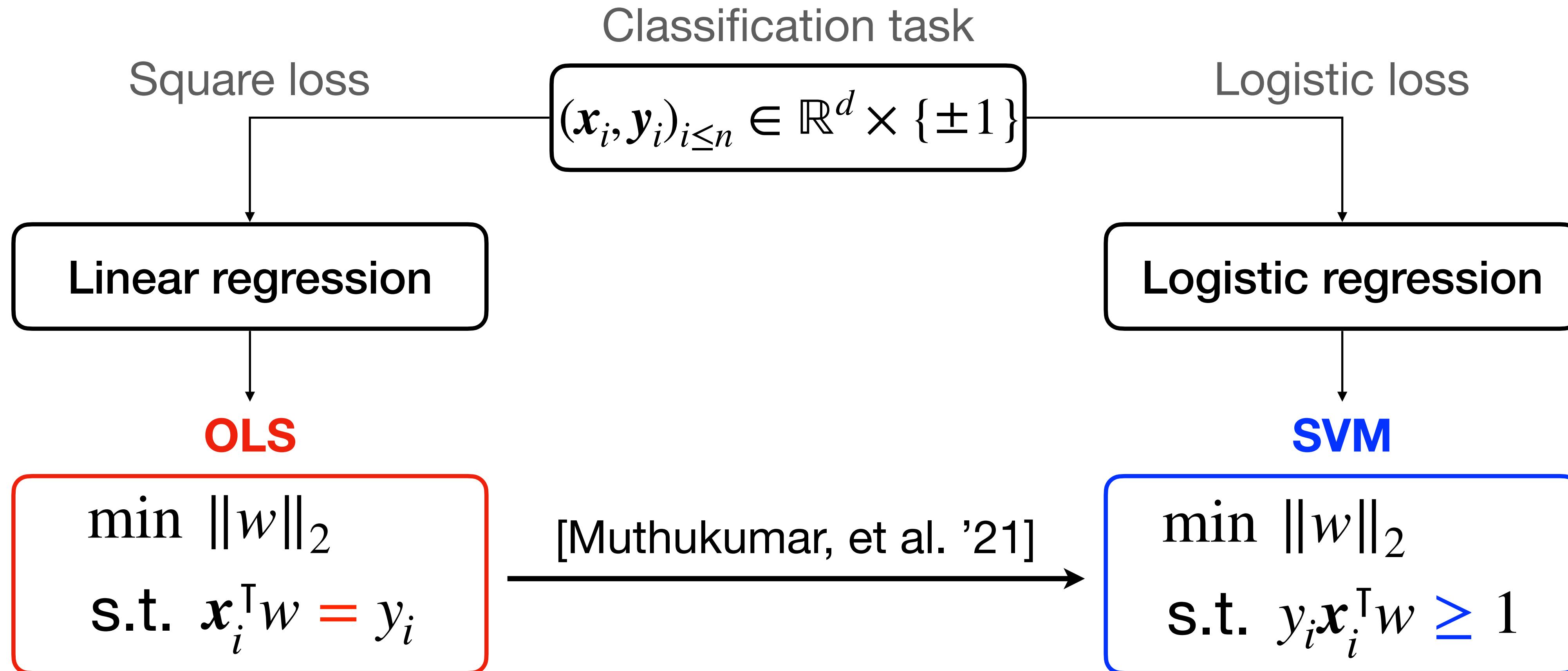
- Similar result hold for  $\ell_p$ -norm hard margin support vector machines ( $\ell_p$ -**SVM**) with Steepest Descent dynamics [Gunasekar, et al. '18].
- In particular  $\ell_1$ -**SVM** is closely related to **infinitely wide 2-layer networks** [Neyshabur, et al. '14] [Chizat, et al. '18] and **Adaboost** [Rosset, et al. '04].

# Inductive bias

- Generalization properties of **OLS** in high dimensions is widely studied and characterized.
- **Benign overfitting in  $\ell_2$ -OLS**  
[Bartlett, et al. '19]  
[Hastie, et al. '19]
- Benign overfitting in  $\ell_1$ -**OLS**  
[Wang, et al. '22][Li, et al. '21]
- Benign overfitting in  $\ell_p$ -**OLS**  
[Wang, et al. '22]
- Less is known regarding generalization properties of hard margin **SVM** in high dimensions.
- **Generalization behavior for  $\ell_2$ -SVM**  
[Muthukumar, et al. '21]  
[Chatterji, et al. '20]
- Generalization behavior for  $\ell_1$ -**SVM**  
[Donhauser, et al. '22][Chinot, et al. '21]
- Generalization behavior for  $\ell_p$ -**SVM**  
[Donhauser, et al. '22]

- Inductive bias of learning
  - Linear and logistic regression
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  - **OLS = SVM** and its implications
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# Classification vs. regression



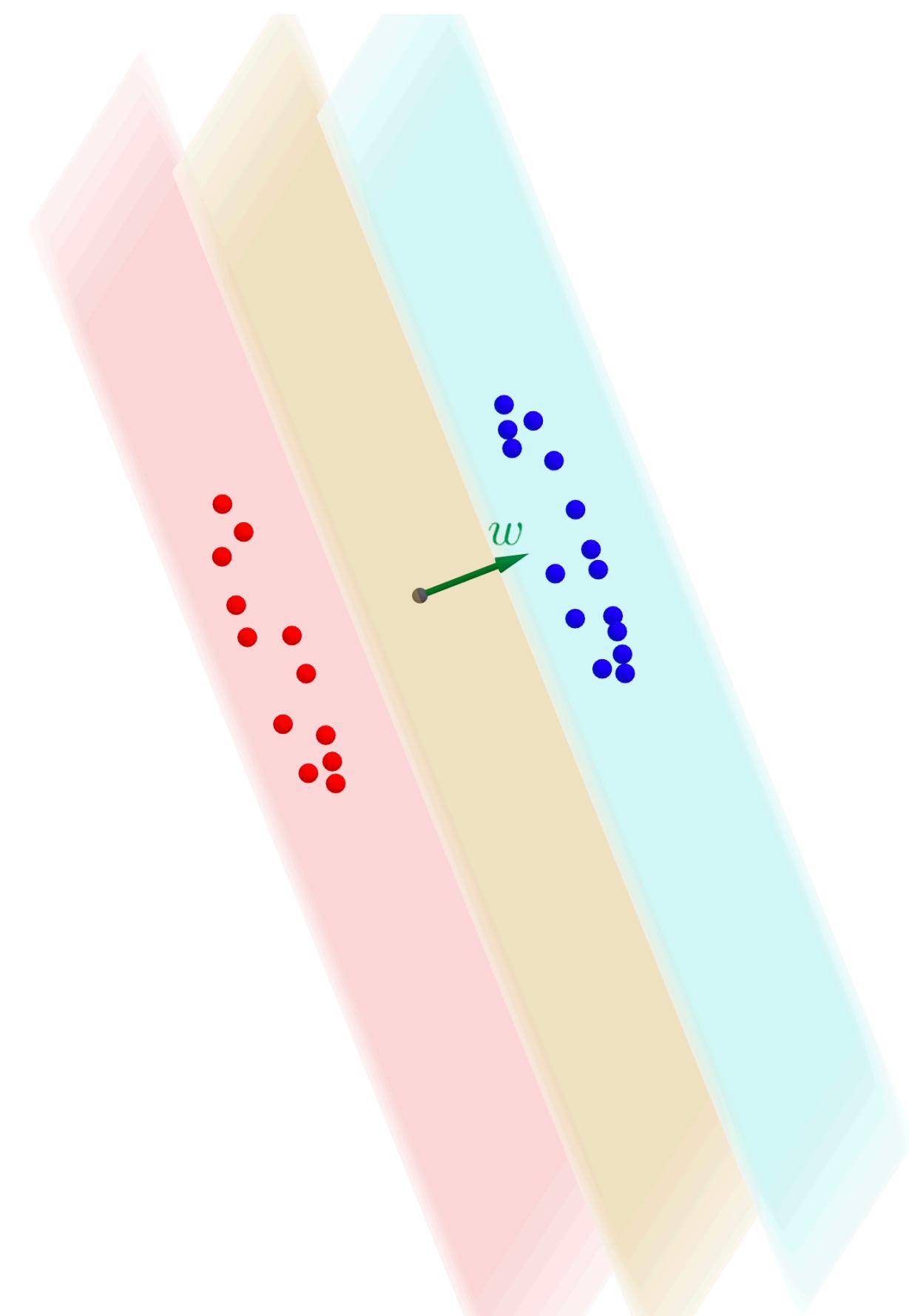
# Classification vs. regression

## Support vector proliferation

- What does **OLS=SVM** mean?
  - **SVM** classifier **interpolates** the data.
  - All samples must become **support vectors**.
- This situation was classically considered to generalize poorly,

**SVM** Complexity  $\leftrightarrow$  # Support Vectors

- However, “Good” generalization properties of **OLS** carries over to **SVM** in these regimes.

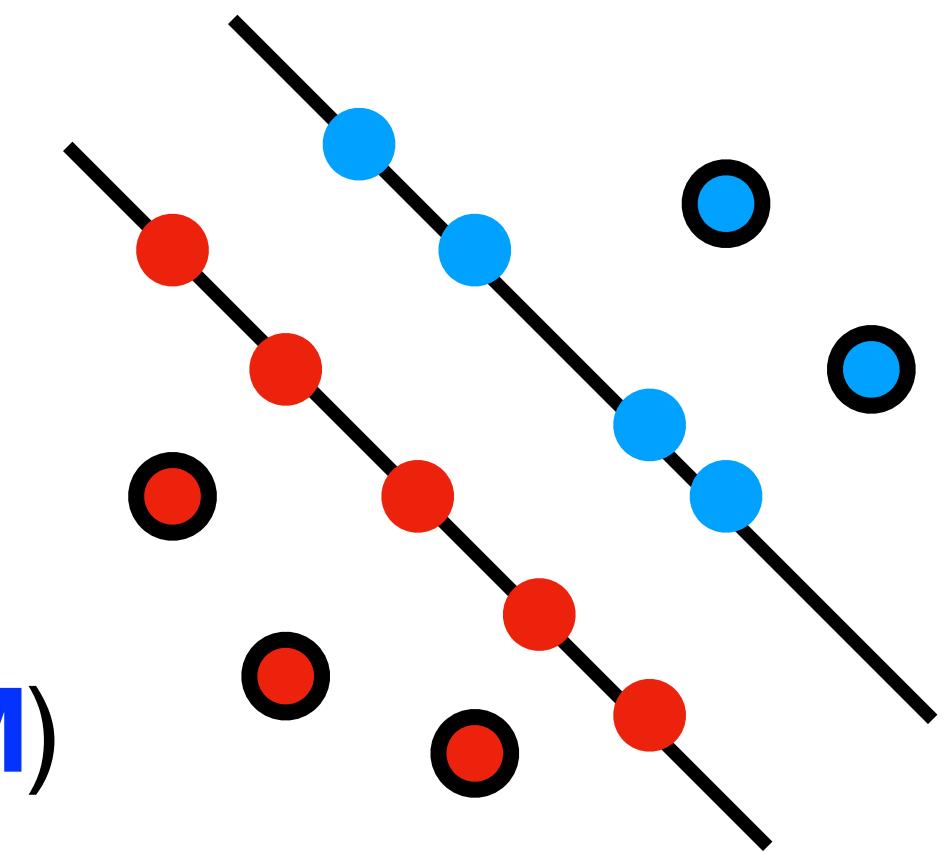


$$\begin{aligned} \min \quad & \|w\|_2 \\ \text{s.t.} \quad & \mathbf{x}_i^T w = y_i \end{aligned}$$

$$\begin{aligned} \min \quad & \|w\|_2 \\ \text{s.t.} \quad & y_i \mathbf{x}_i^T w \geq 1 \end{aligned}$$

# Classical **SVM** generalization bounds

- **SVM** Complexity  $\leftrightarrow$  # Support Vectors
- When fraction of support vectors is  $o(1)$ , then **SVM** generalizes. [Graepel, et al. '05]
  - Sample compression based bounds.
  - Dropping non support vector samples still yields the **SVM** same classifier
  - Distribution free, thus widely applicable.
- This sparsity in #SV can happen in **underparameterized** asymptotic regimes.
- Different story in overparameterized regimes (e.g. when **OLS=SVM**)



# OLS = SVM and its implications

- “Good” generalization properties of **OLS** carries over to **SVM** in these regimes.

$$\mathbb{P} [yh_w(x) < 0] \leq \mathbb{E} [(1 - yh_w(x))^2]$$

- Classification is (thought of to be) “easier” than regression.

Regression consistency  $\implies$  Classification consistency

- Using this coincidence [Muthukumar, et al. '21] shows a regime where classification is consistent but not regression, under a spiked covariance model on features.

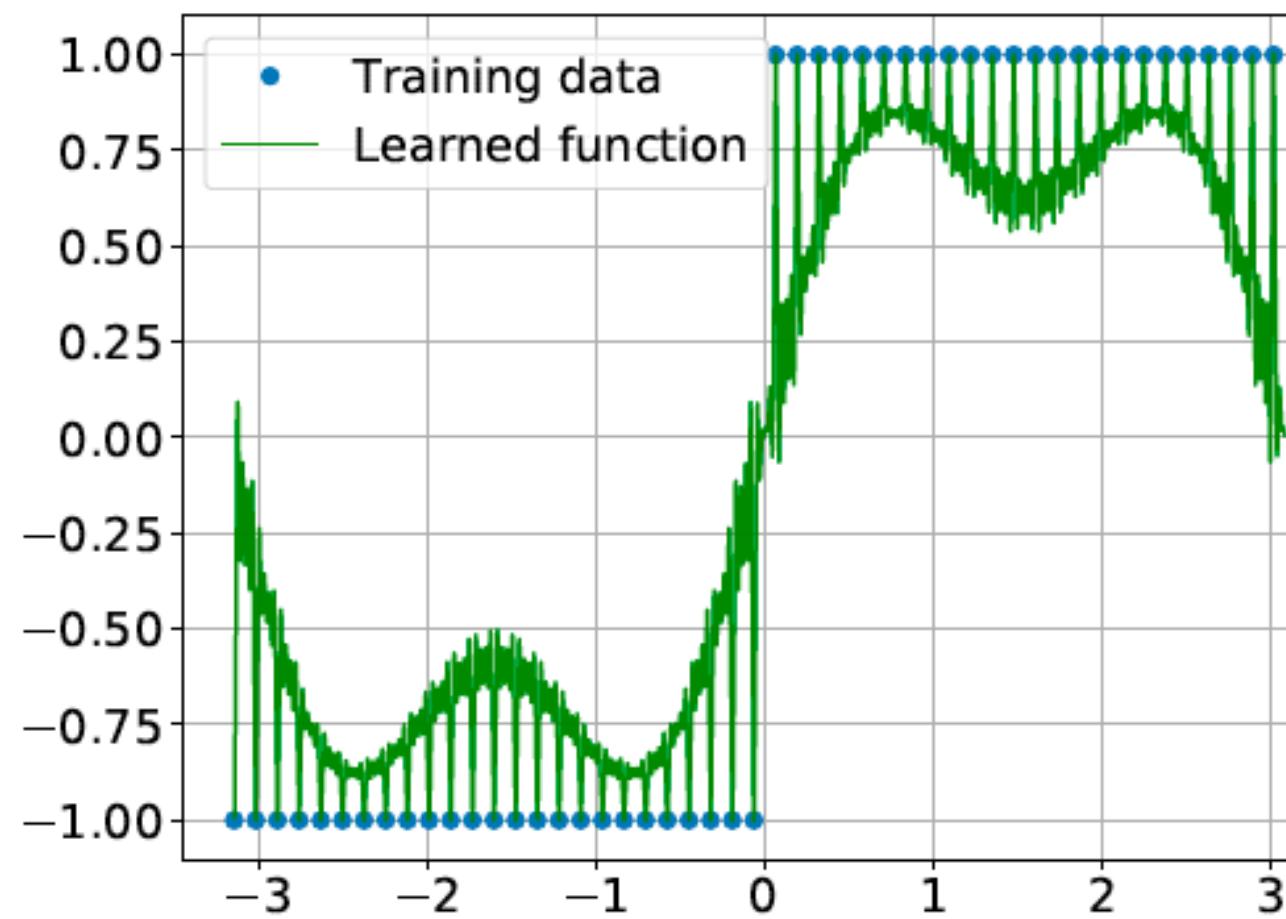


Fig. From [Muthukumar, et al. '21]

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# Our results

- **Data model:** Labels are fixed and features are anisotropic Gaussian

$$x_i \sim \mathcal{N}(0, \Sigma) \in \mathbb{R}^d, y_i \in \{\pm 1\}, 1 \leq i \leq n$$

- **Effective ranks:** let  $\lambda_1 \geq \lambda_2 \geq \dots \geq \lambda_d$  be the eigenvalues of  $\Sigma$

$$d_{eff} = \left( \frac{\text{tr}(\Sigma)}{\|\Sigma\|_F} \right)^2 = \left( \frac{\|\lambda\|_1}{\|\lambda\|_2} \right)^2, \quad d_\infty = \frac{\text{tr}(\Sigma)}{\|\Sigma\|_{op}} = \frac{\|\lambda\|_1}{\|\lambda\|_\infty}$$

## Theorem: [Our work]

Given  $n$  samples (as above) assume  $d_{eff} = O(n \log n)$ ,  $d_\infty = \Omega(n)$ , and the absence of a single strong feature, then w.h.p. **OLS**  $\neq$  **SVM**.

- For isotropic Gaussian features  $d_{eff} = d_\infty = d$

# Comparison with previous works

**Question:** For what  $d_{eff} = d_{eff}(n)$  do we have **OLS=SVM** with high probability?

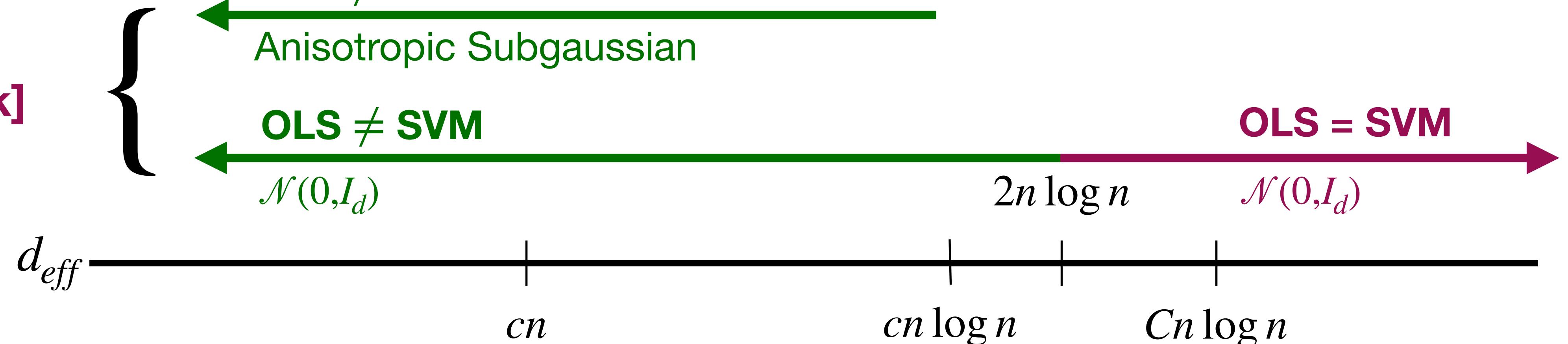
- [Muthukumar, et al. '20]

$$\frac{\text{OLS} = \text{SVM}}{\mathcal{N}(0, \Sigma)}$$

- [Hsu, et al. '21]

$$\frac{\text{OLS} \neq \text{SVM}}{\mathcal{N}(0, I_d)}$$

- [Our work]



# Asymptotic comparisons

**Theorem: [Buhot, et al. '01]**

For isotropic Gaussian features in the proportional regime  $d(n) = \alpha n$ , then the fraction of support vectors in the **SVM** converges w.h.p to,

$$\lim_{n \rightarrow \infty} \frac{\#\text{SV}}{n} = \begin{cases} 0.952\alpha & \alpha \ll 1 \quad (\text{Underparameterized}) \\ 1 - \sqrt{\frac{2}{\pi\alpha}} e^{-\frac{\alpha}{2}} & \alpha \gg 1 \quad (\text{Overparameterized}) \end{cases}$$

**Theorem: [Our work]**

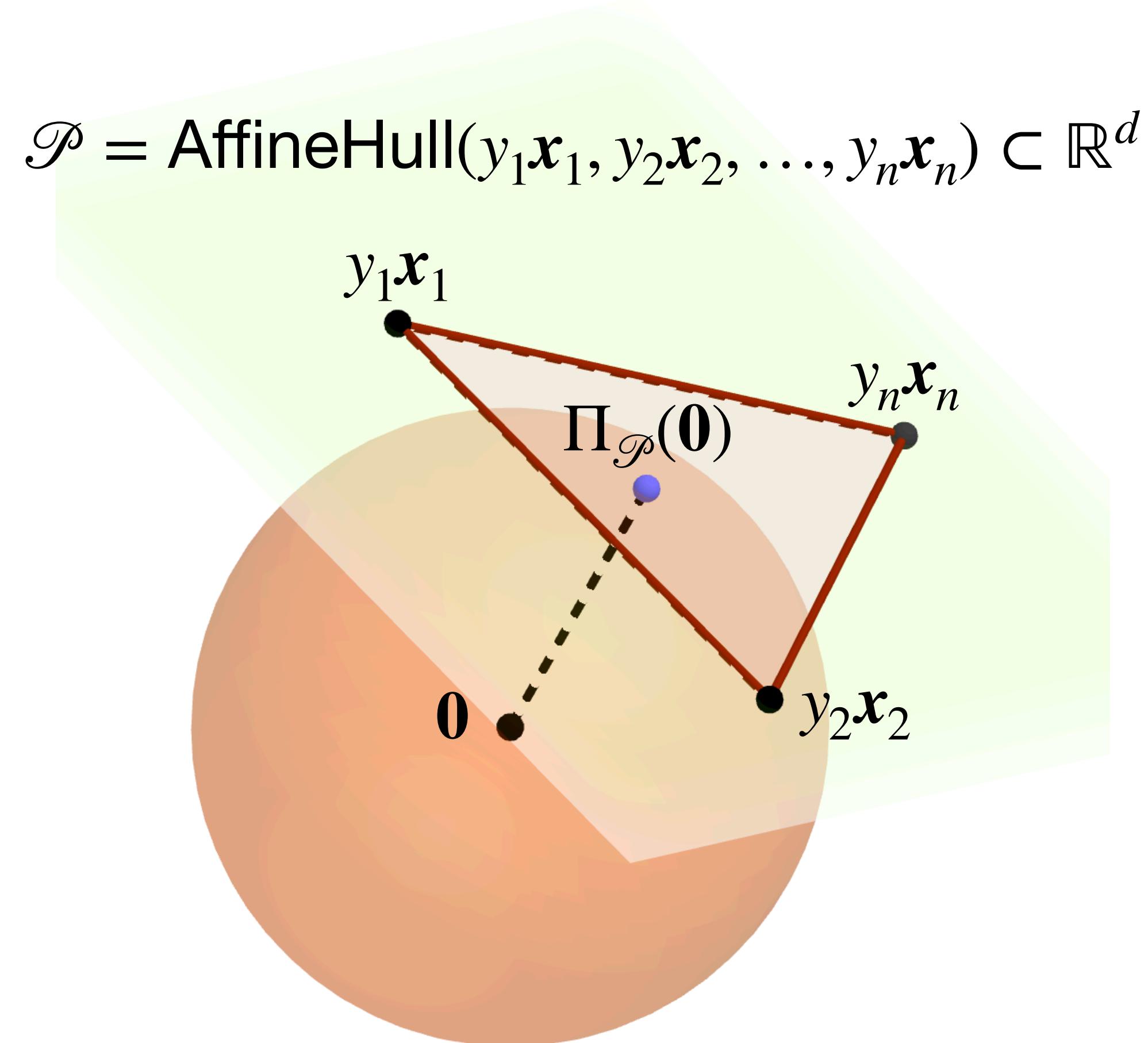
For isotropic Gaussian data in the regime where  $d(n) = \tau n \log n$ ,

$$\lim_{n \rightarrow \infty} \mathbb{P} \left[ \frac{\#\text{SV}}{n} = 1 \right] = \begin{cases} 0 & \tau < 2 \\ 1 & \tau > 2 \end{cases}$$

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# Geometrical Intuition

- The **OLS=SVM** occurrence is equivalent to,  
 $\Pi_{\mathcal{P}}(\mathbf{0}) \in \text{ConvHull}(y_1\mathbf{x}_1, \dots, y_n\mathbf{x}_n)$ .
- For isotropic gaussian features with  $d \gg n$ , all samples ( $y_i\mathbf{x}_i$ 's) are on the convex hull.
- $\|\mathbf{x}_i\|_2$  is roughly the same for all the samples.
- The convex hull is almost a regular polygon.
- Intuitively, larger  $d$  increases the probability of this occurrence.



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# Proof ideas

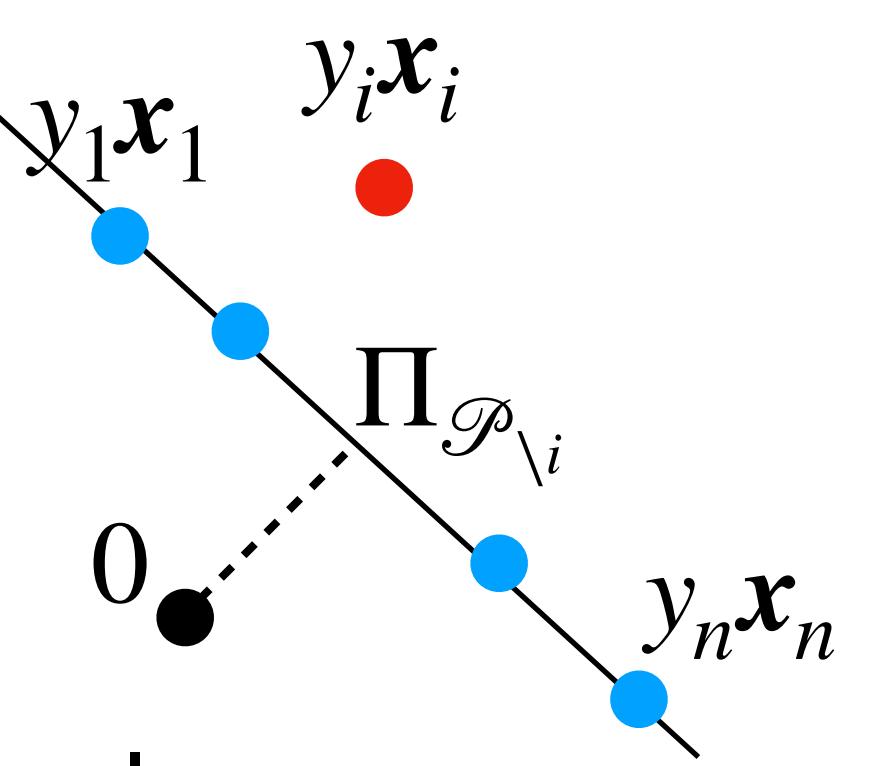
Features for sample i	$\mathbf{x}_i$
Label for sample i	$y_i$
Affine space when sample i is excluded.	$\mathcal{P}_{\setminus i}$

**Key lemma [Hsu, et al. '20][Our work]**

Let  $\Pi_{\mathcal{P}}$  be the projection onto  $\mathcal{P} = \text{AffineHull}(y_1\mathbf{x}_1, \dots, y_n\mathbf{x}_n)$  using  $\ell_2$ -norm.

$$\max_{i \leq n} \left\{ \left\langle y_i \mathbf{x}_i, \frac{\Pi_{\mathcal{P}_{\setminus i}}(\mathbf{0})}{\|\Pi_{\mathcal{P}_{\setminus i}}(\mathbf{0})\|_2^2} \right\rangle \right\} < 1 \iff \text{OLS} = \text{SVM} \iff \Pi_{\mathcal{P}}(\mathbf{0}) \in \text{ConvHull}(y_1\mathbf{x}_1, \dots, y_n\mathbf{x}_n)$$

- **Proof intuition:**  $w_{\text{OLS}}^{(i)} = \frac{\Pi_{\mathcal{P}_{\setminus i}}(\mathbf{0})}{\|\Pi_{\mathcal{P}_{\setminus i}}(\mathbf{0})\|_2^2}$  using duality.
- $\langle u, w_{\text{OLS}}^{(i)} \rangle - 1$  is a hyperplane passing through  $\mathcal{P}_{\setminus i}$
- Origin and the i'th sample should be on the same side of this hyperplane.
- Otherwise the i'th sample is “unnecessary” for **SVM**



Features for sample i	$\mathbf{x}_i$
Label for sample i	$y_i$
Affine space when sample i is excluded	$\mathcal{P}_{\setminus i}$
Collection of samples except I	$\mathbf{X}_{\setminus i}$

# Proof ideas

**Key lemma [Hsu, et al. '20][Our work]**

Let  $\Pi_{\mathcal{P}}$  be the projection onto  $\mathcal{P} = \text{AffineHull}(y_1\mathbf{x}_1, \dots, y_n\mathbf{x}_n)$  using  $\ell_2$ -norm.

$$\max_{i \leq n} \left\{ \left\langle y_i \mathbf{x}_i, \frac{\Pi_{\mathcal{P}_{\setminus i}}(\mathbf{0})}{\|\Pi_{\mathcal{P}_{\setminus i}}(\mathbf{0})\|_2^2} \right\rangle \right\} < 1 \iff \text{OLS} = \text{SVM} \iff \Pi_{\mathcal{P}}(\mathbf{0}) \in \text{ConvHull}(y_1\mathbf{x}_1, \dots, y_n\mathbf{x}_n)$$

- For  $\ell_2$  explicit solutions for **OLS** is known:

$$w_{\text{OLS}}^{(i)} = \frac{\Pi_{\mathcal{P}_{\setminus i}}(\mathbf{0})}{\|\Pi_{\mathcal{P}_{\setminus i}}(\mathbf{0})\|_2^2} = \mathbf{X}_{\setminus i}^\top \left( \mathbf{X}_{\setminus i} \mathbf{X}_{\setminus i}^\top \right)^{-1} \mathbf{y}_{\setminus i}$$

- We use this lemma to prove lower bounds on the dimension.

Features for sample i	$\mathbf{x}_i$
Label for sample i	$y_i$
Collection of Features except	$X_{\setminus i}$
Collection of labels except sample i	$y_{\setminus i}$

# Proof ideas

- **Question:** For what values  $d = d(n)$  do we have the following with high probability?

$$\max_{i \leq n} \left\{ \underbrace{\left\langle y_i \mathbf{x}_i, X_{\setminus i}^T \left( X_{\setminus i} X_{\setminus i}^T \right)^{-1} y_{\setminus i} \right\rangle}_{z_i} \right\} < 1$$

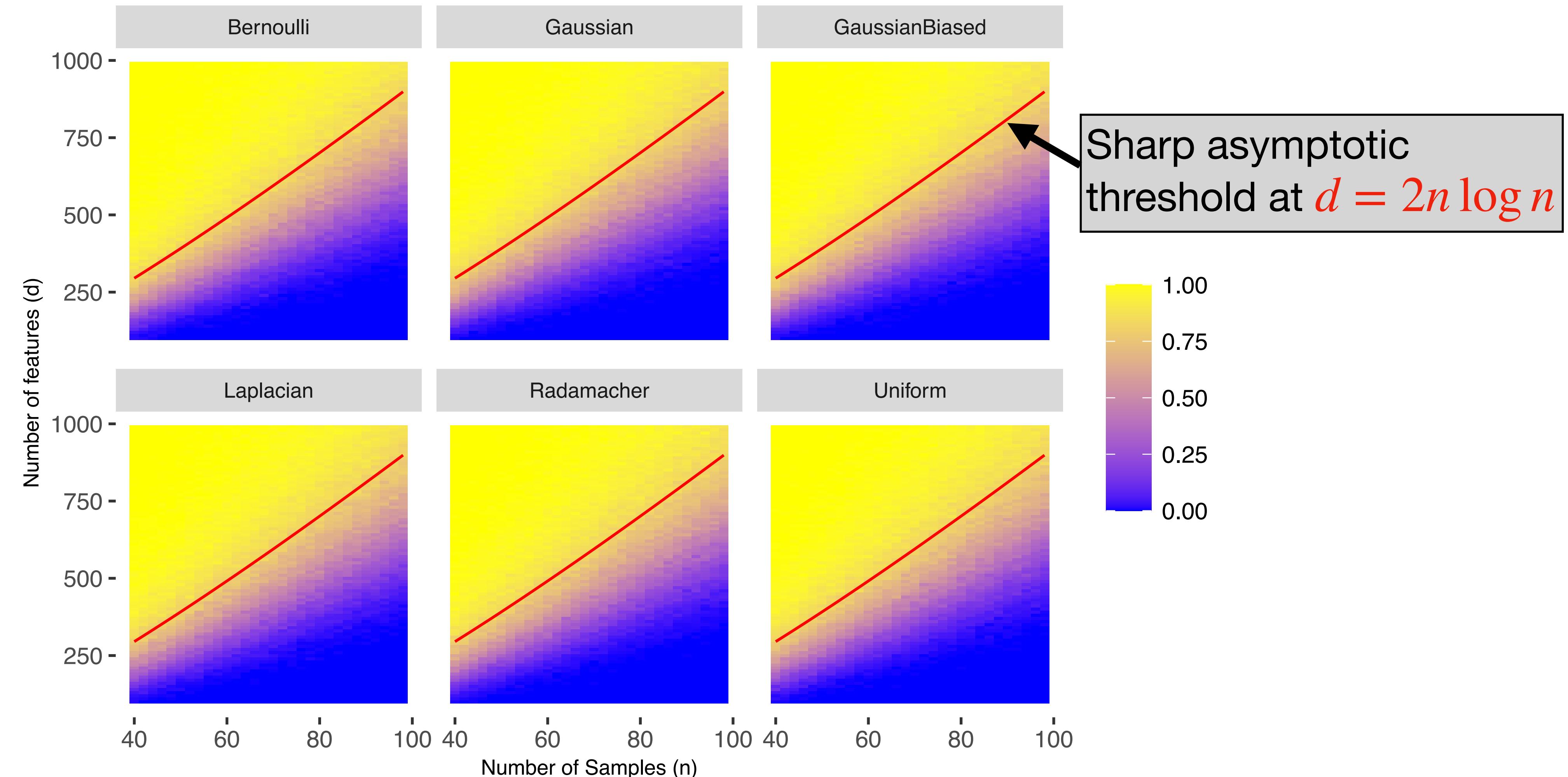
- $z_i$  behaves roughly as a  $\mathcal{N}\left(0, \frac{n}{d}\right)$ .

- if  $z_i$ 's were independent:  $\max_{i \leq n} z_i = \Theta_p\left(\sqrt{\frac{2n \log n}{d}}\right)$  Critical threshold  $\implies d = \Theta(n \log(n))$
- The **correlation** among  $z_i$ 's are weak  $\Theta\left(\frac{1}{d}\right)$ , thus behavior stays the same.

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# Empirical evidence for universality

- Universality of **SVP** phenomenon (**SVM** = **OLS**) under different feature distributions



Number of samples.	$n$
Number of features	$d$
Distribution under which features are generated from.	$\mathcal{D}$
Probit link function	$\Phi$

# Empirical evidence for universality

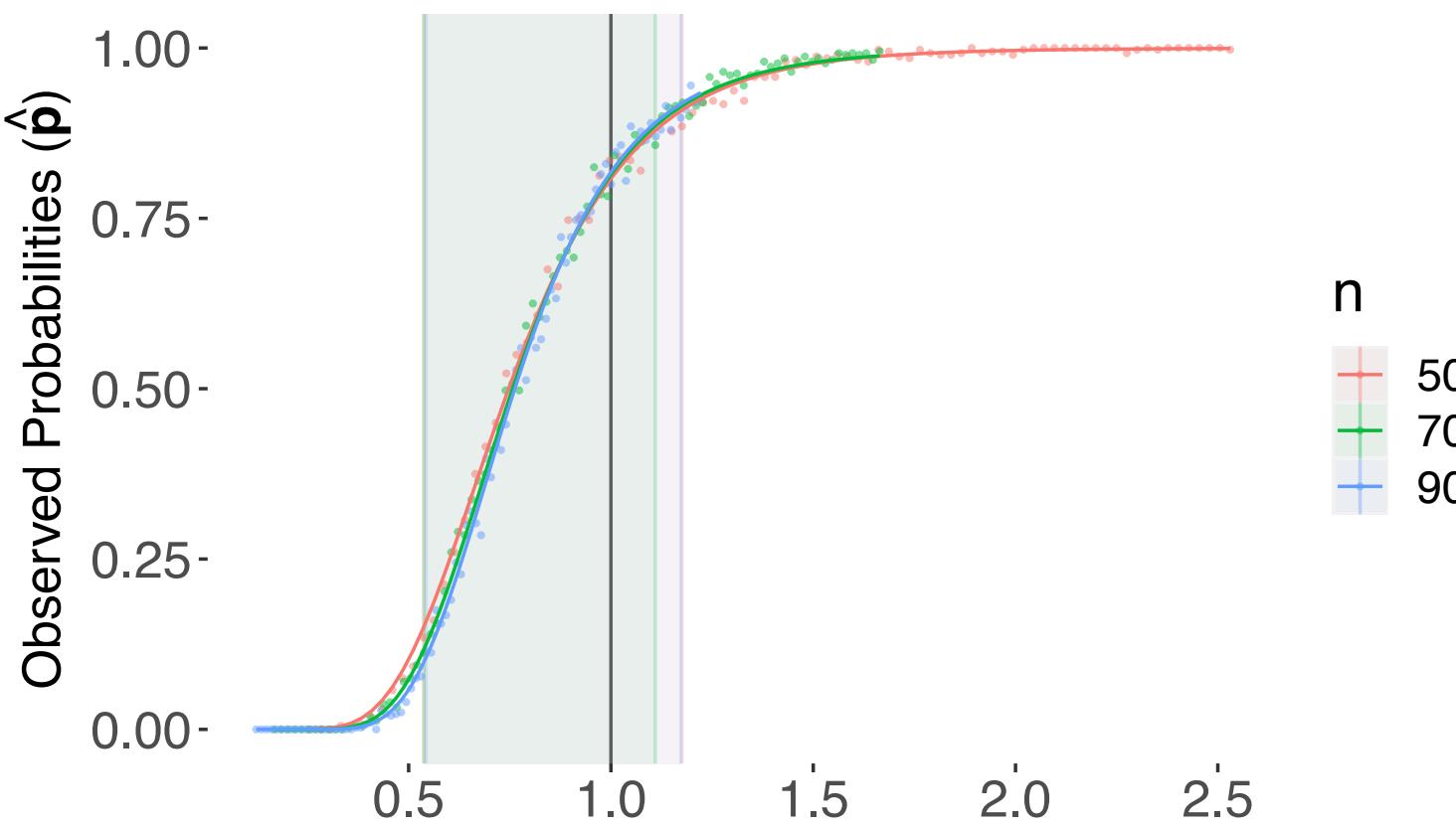
- Statistical methodology inspired by [Donoho, et al. 09]
- We use Probit regression to model the observed probability of **OLS=SVM**.

$$p(n, d; \mathcal{D}) = \Phi(\mu^{(0)}(n, \mathcal{D}) + \mu^{(1)}(n, \mathcal{D})\tau + \mu^{(2)}(n, \mathcal{D})\log \tau)$$

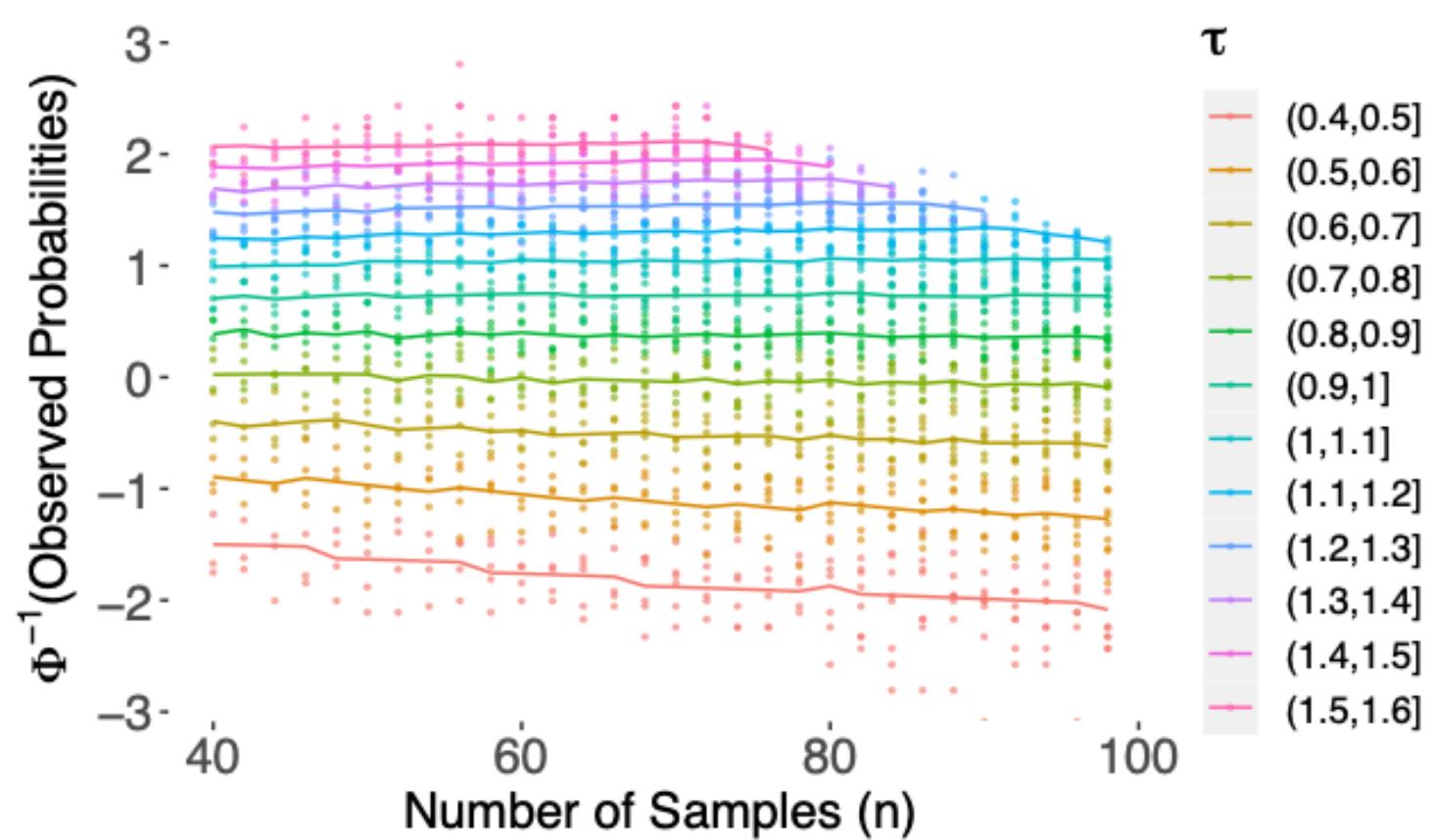
$$\mu^{(i)}(n, \mathcal{D}) = \mu_0^{(i)}(\mathcal{D}) + \frac{\mu_1^{(i)}(\mathcal{D})}{\sqrt{n}}$$

- Perform sequential hypothesis test using ANOVA.

$$\begin{cases} M_0 : \mu_j^{(i)}(\mathcal{D}) = \mu_{j'}^{(i)} & \Rightarrow \text{Reject} \\ M_1 : \mu_0^{(i)}(\mathcal{D}) = \mu_0^{(i')} & \Rightarrow \text{Fail to reject} \\ M_2 : \text{O.W.} & \end{cases}$$



$$\tau = \frac{d}{2n \log n}$$



# Open questions

- When does **SVM** = **OLS** for other norms?

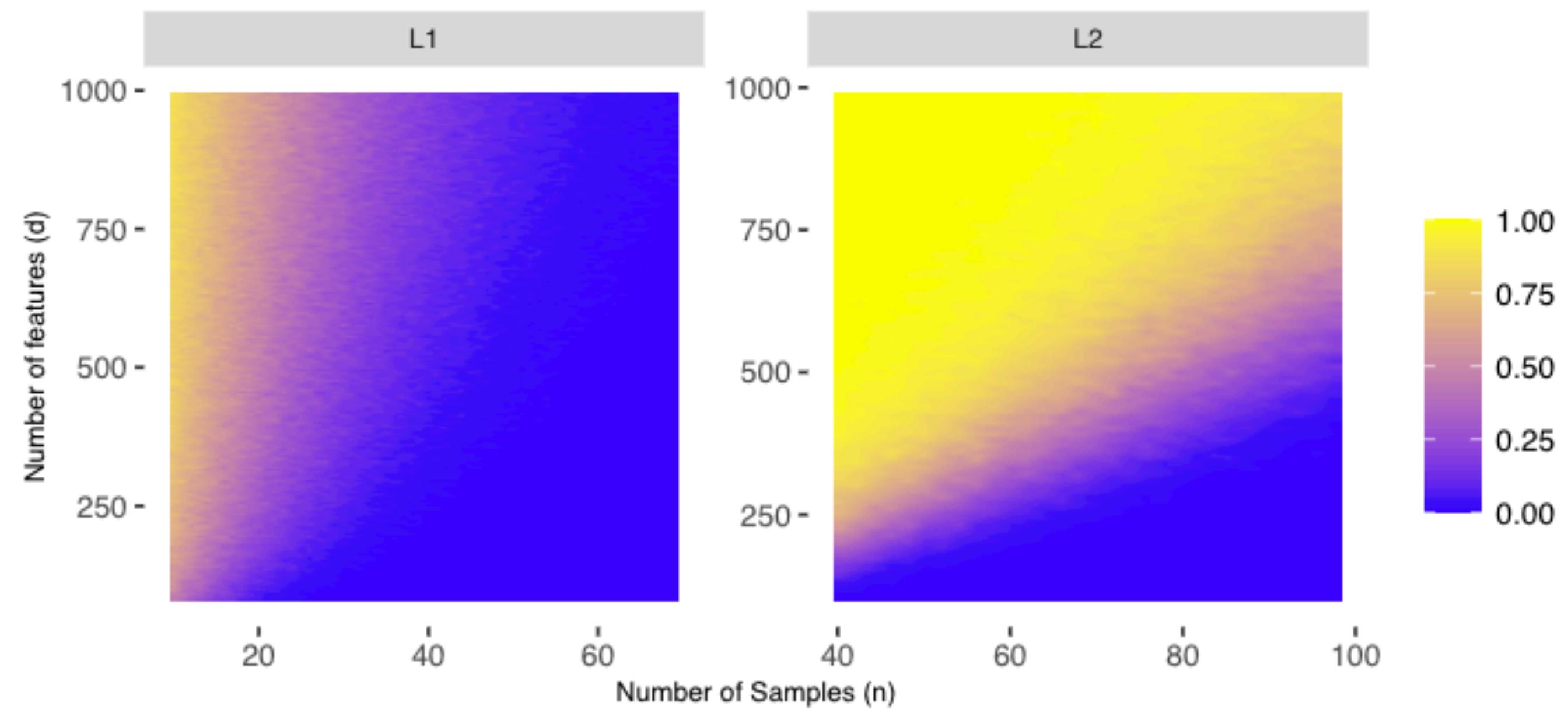
$$\min \|w\|_p$$

$$\text{s.t. } y_i \mathbf{x}_i^\top w \geq 1$$

$$\min \|w\|_p$$

$$\text{s.t. } \mathbf{x}_i^\top w = y_i$$

- Conjecture: For  $p = 1$ , **SVM** = **OLS** still occurs but the threshold is much larger function of number of samples  $n$ .
- Theoretical understanding of universality.



**Thank you!**